

## FS10SM-10-VB Datasheet

# N-Channel 600V (D-S) Super Junction MOSFET

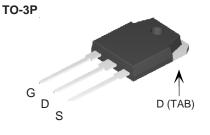
PRODUCT SUMMARY						
V <sub>DS</sub> (V) at T <sub>J</sub> max.	650					
R <sub>DS(on)</sub> at 25 °C (Ω)	$V_{GS} = 10 V$	0.38				
Q <sub>g</sub> max. (nC)	38					
Q <sub>gs</sub> (nC)	4					
Q <sub>gd</sub> (nC)	4.2					
Configuration	Single					

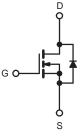
## **FEATURES**

- Low figure-of-merit (FOM) Ron x Qa
- Low input capacitance (Ciss)
- Reduced switching and conduction losses
- Ultra low gate charge (Q<sub>a</sub>)
- Avalanche energy rated (UIS)

### **APPLICATIONS**

- Server and telecom power supplies
- Switch mode power supplies (SMPS)
- Power factor correction power supplies (PFC)
- Lighting
  - High-intensity discharge (HID)
  - Fluorescent ballast lighting
- Industrial





N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T <sub>C</sub>	= 25 °C, unl	ess otherwis	se noted)		
PARAMETER			SYMBOL	LIMIT	UNIT
Drain-Source Voltage			V <sub>DS</sub>	600	v
Gate-Source Voltage			V <sub>GS</sub>	± 30	v
Continuous Drain Current (T <sub>J</sub> = 150 °C)	V =+ 10 V	T <sub>C</sub> = 25 °C	- I <sub>D</sub>	11	
	V <sub>GS</sub> at 10 V	$10 \text{ V}  \frac{\text{T}_{\text{C}} = 25 \text{ °C}}{\text{T}_{\text{C}} = 100 \text{ °C}}$		9.7	А
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	50	
Linear Derating Factor				1.67/1.5/0.3	W/°C
Single Pulse Avalanche Energy <sup>b</sup>			E <sub>AS</sub>	132	mJ
Maximum Power Dissipation			PD	83/83/31	W
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C
Drain-Source Voltage Slope	T <sub>J</sub> = 125 °C		-D (/-D	50	
Reverse Diode dV/dt <sup>d</sup>			dV/dt	3.1	V/ns
Soldering Recommendations (Peak Temperature) <sup>c</sup>	for 10 s			300	°C

#### Notes

a. Repetitive rating; pulse width limited by maximum junction temperature. b.  $V_{DD} = 50$  V, starting T<sub>J</sub> = 25 °C, L = 28.2 mH, R<sub>g</sub> = 25  $\Omega$ , I<sub>AS</sub> = 4.5 A.

c. 1.6 mm from case.

d.  $I_{SD} \leq I_D$ , dI/dt = 100 A/µs, starting  $T_J$  = 25 °C.





THERMAL RESISTANCE RATI	NGS							
PARAMETER	SYMBOL	TYP.		MAX.		UNIT		
Maximum Junction-to-Ambient	R <sub>thJA</sub>	- 60						
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-		0.6		°C/W		
<b>SPECIFICATIONS</b> (T <sub>J</sub> = 25 $^{\circ}$ C, u	nless otherwi	se noted)						
PARAMETER	SYMBOL	TES	T CONDIT	IONS	MIN.	TYP.	MAX.	UNIT
Static		+			•		•	•
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> =	= 0 V, I <sub>D</sub> =	250 µA	600	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C,	I <sub>D</sub> = 1 mA	-	0.65	-	V/°C
Gate-Source Threshold Voltage (N)	V <sub>GS(th)</sub>	V <sub>DS</sub> =	= V <sub>GS</sub> , I <sub>D</sub> =	250 µA	2	-	4	V
		$V_{GS} = \pm 20 V$ $V_{GS} = \pm 30 V$		-	-	± 100	nA	
Gate-Source Leakage	I <sub>GSS</sub>			-	-	± 1	μA	
Zaus Osta Valtare Duris O such		V <sub>DS</sub> =	= 650 V, V <sub>G</sub>	<sub>as</sub> = 0 V	-	-	1	<u> </u>
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 520 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C		-	-	10	μA	
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	$V_{GS} = 10 V$		I <sub>D</sub> = 5 A	-	0.38	-	Ω
Forward Transconductance	<b>g</b> fs	V <sub>DS</sub>	= 30 V, I <sub>D</sub>	= 5 A	-	16	-	S
Dynamic					•		•	
Input Capacitance	C <sub>iss</sub>		V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 100 V,		-	680	-	-
Output Capacitance	Coss	-			-	140	-	
Reverse Transfer Capacitance	C <sub>rss</sub>	f = 1 MHz		-	5	-	pF	
Effective Output Capacitance, Energy Related <sup>a</sup>	C <sub>o(er)</sub>	$V_{DS} = 0 V $ to 520 V, $V_{GS} = 0 V$		-	63	-		
Effective Output Capacitance, Time Related <sup>b</sup>	C <sub>o(tr)</sub>			-	113	-		
Total Gate Charge	Qg				-	38	56	
Gate-Source Charge	Q <sub>gs</sub>	$V_{GS} = 10 \text{ V}$ $I_D = 5 \text{ A}, V_{DS} = 520 \text{ V}$		-	4	-	nC	
Gate-Drain Charge	Q <sub>gd</sub>				-	4.5	-	
Turn-On Delay Time	t <sub>d(on)</sub>	$V_{DD}$ = 520 V, $I_D$ = 5 A, $V_{GS}$ = 10 V, $R_g$ = 9.1 $\Omega$		-	13	25	- ns	
Rise Time	t <sub>r</sub>			-	11	35		
Turn-Off Delay Time	t <sub>d(off)</sub>			-	81	90		
Fall Time	t <sub>f</sub>			-	25	40		
Gate Input Resistance	R <sub>g</sub>	f = 1 MHz, open drain		-	3.5	-	Ω	
Drain-Source Body Diode Characteristic	s							
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	11	A	
Pulsed Diode Forward Current	I <sub>SM</sub>			-	-	55		
Diode Forward Voltage	V <sub>SD</sub>	T <sub>J</sub> = 25 °C, I <sub>S</sub> = 5 A, V <sub>GS</sub> = 0 V		-	-	1.5	V	
Reverse Recovery Time	t <sub>rr</sub>	$T_J = 25 \text{ °C}, I_F = I_S = 5 \text{ A},$ dl/dt = 100 A/µs, V <sub>R</sub> = 400 V		-	270	-	ns	
Reverse Recovery Charge	Q <sub>rr</sub>			-	3.3	-	μC	
Reverse Recovery Current	I <sub>RRM</sub>			-	30	-	A	

#### Notes

a.  $C_{oss(er)}$  is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ . b.  $C_{oss(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ .



## TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

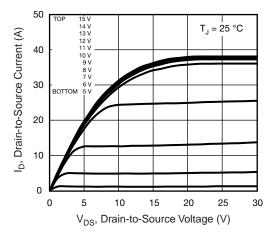


Fig. 1 - Typical Output Characteristics

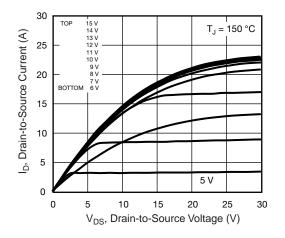


Fig. 2 - Typical Output Characteristics

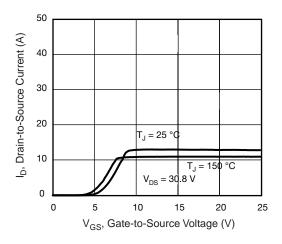


Fig. 3 - Typical Transfer Characteristics

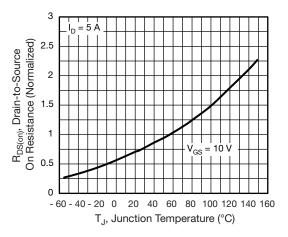


Fig. 4 - Normalized On-Resistance vs. Temperature

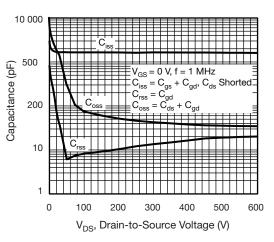


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

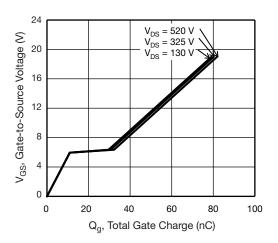


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

# FS10SM-10-VB



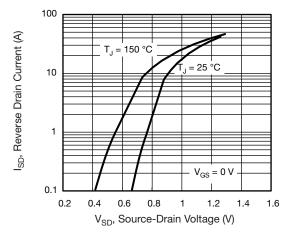
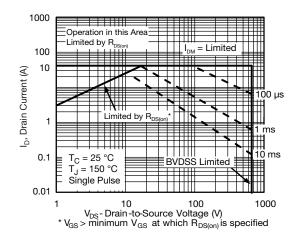


Fig. 7 - Typical Source-Drain Diode Forward Voltage





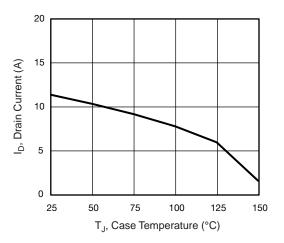


Fig. 9 - Maximum Drain Current vs. Case Temperature

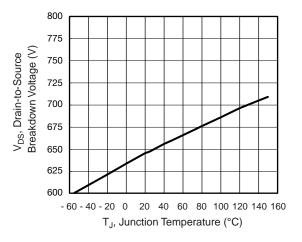


Fig. 10 - Temperature vs. Drain-to-Source Voltage

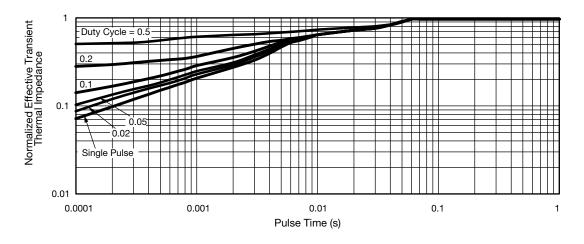


Fig. 11 - Normalized Thermal Transient Impedance, Junction-to-Case



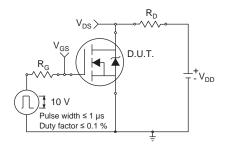


Fig. 12 - Switching Time Test Circuit

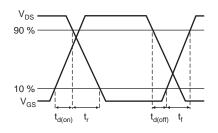


Fig. 13 - Switching Time Waveforms

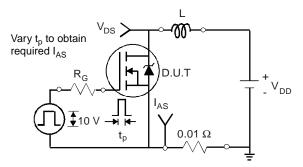


Fig. 14 - Unclamped Inductive Test Circuit

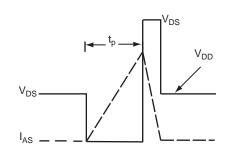


Fig. 15 - Unclamped Inductive Waveforms

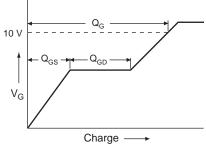


Fig. 16 - Basic Gate Charge Waveform

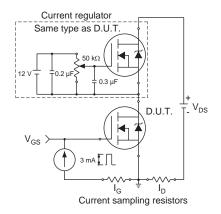
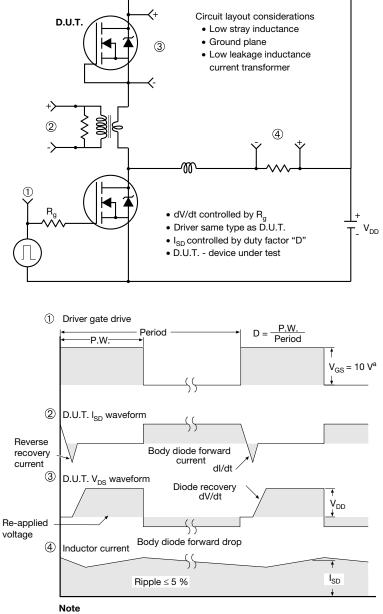


Fig. 17 - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit

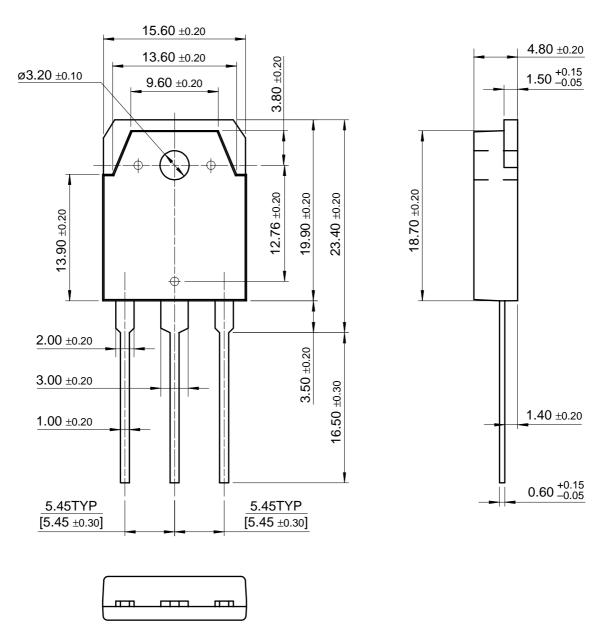


a.  $V_{GS} = 5$  V for logic level devices

Fig. 18 - For N-Channel



TO-3P





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